

# **Notice of References Cited**

Application/Control No.

09/868,239

Applicant(s)/Patent Under  
Reexamination  
ACKERMANN ET AL.

Examiner

Trang H. Cao

Art Unit

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## **U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY		
	A	US-2001/0013008	08-2001	WACLAWSKI, ANTHONY C.	705/10
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number	Date	Country	Name	Classification
		Country Code-Number-Kind Code	MM-YYYY			
	N					
	O					
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	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

	U	S. Yamada et al.; "SOFTWARE RELIABILITY GROWTH MODELING: MODELS AND APPLICATIONS"; IEEE Transaction on Software Engineering, Vol. SE-11, No. 12, December 1985, pages 1431-1437				
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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